

Search Notes

Application/Control No.

10/565,394

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

KOBAYASHI ET AL.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
180	89.2 309	9/12/2007	HP
	296		
	219		
181	250	9/12/2007	HP
	207		
	273		
	227		
60	322	9/12/2007	HP
	299		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR